

# GD54/74LS109A

## DUAL POSITIVE-EDGE-TRIGGERED J-K FLIP-FLOPS

### Feature

- Positive Edge-Triggering
- Direct Set and reset inputs
- J and  $\bar{K}$  inputs
- Q and  $\bar{Q}$  outputs

### Description

This device contains two independent positive-edge-triggered J-K flip-flops with complementary outputs. The J and K data is accepted by the flip-flop on the rising edge of the clock pulse. The triggering occurs at a voltage level and is not directly related to the transition time of the rising edge of the clock. The data on the J and K inputs may be changed while the clock is high or low as long as setup and hold times are not violated. A low logic level on the preset or clear inputs will set or reset the outputs regardless of the logic levels of the other inputs.

### Function Table

Inputs			Outputs	
PR	CLR	CLK	J	$\bar{K}$
L	H	X	X	X
H	L	X	X	X
L	L	X	X	X
H	H	↑	L	L
H	H	↑	H	L
H	H	↑	L	H
H	H	↑	H	H
H	H	L	X	X

X = Either Low or High Logic Level

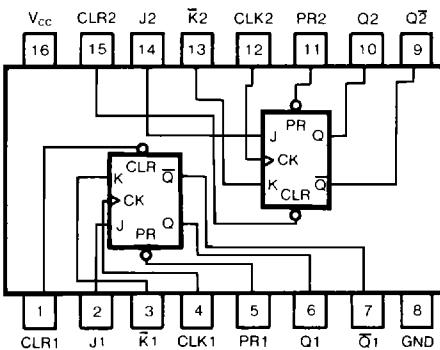
↑ = Rising Edge of Pulse

\* = This configuration is nonstable, that is it will not persist when preset and/or clear inputs return to their inactive (high) state.

Q<sub>0</sub> = The output logic level of Q before the indicated input conditions were established

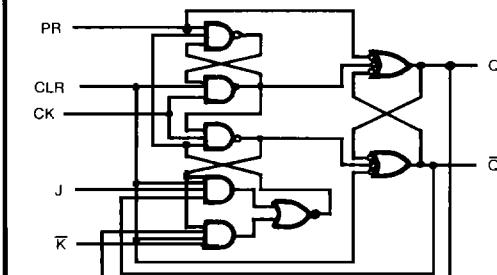
Toggle = Each output changes to the complement of its previous level on each active transition of the clock pulse

### Pin Configuration



Suffix-Blank. Plastic Dual In Line Package  
Suffix-J Ceramic Dual In Line Package

### Functional Block Diagram



### Absolute Maximum Ratings

- Supply voltage, V<sub>cc</sub> ..... 7V
- Input voltage ..... 7V
- Operating free-air temperature range 54LS ..... -55°C to 125°C  
74LS ..... 0°C to 70°C
- Storage temperature range ..... -65°C to 150°C

**Recommended Operating Conditions**

SYMBOL	PARAMETER		MIN	NOM	MAX	UNIT	
$V_{CC}$	Supply voltage		54	4.5	5	5.5	
			74	4.75	5	5.25	
$I_{OH}$	High-level output current		54,74	-400		$\mu A$	
$I_{OL}$	Low-level output current		54	4		mA	
			74	8			
$f_{clock}$	Clock frequency		0		25	MHz	
$t_W$	Pulse Width	Clock High	18			ns	
		Preset Low	15				
		Clear Low	15				
$t_{SU}$	Setup Time	Data High	30 $\uparrow$			ns	
		Data Low	20 $\uparrow$				
$t_H$	Hold Time		0 $\uparrow$			ns	
$T_A$	Operating free-air temperature		54	-55	125	°C	
			74	0	70		

**Electrical Characteristics** over recommended operating free-air temperature range (unless otherwise noted)

SYMBOL	PARAMETER	TEST CONDITIONS	MIN	TYP (Note 1)	MAX	UNIT
$V_{IH}$	High-level input voltage			2		V
$V_{IL}$	Low-level input voltage		54		0.7	V
			74		0.8	
$V_{IK}$	Input clamp voltage	$V_{CC} = \text{Min}$ , $I_i = -18\text{mA}$			-1.5	V
$V_{OH}$	High level output voltage	$V_{CC} = \text{Min}$ , $V_{IL} = \text{Max}$ $I_{OH} = \text{Max}$ , $V_{IH} = \text{Min}$	54	2.5	3.4	V
			74	2.7	3.4	
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{Min}$ $V_{IL} = \text{Max}$ $V_{IH} = \text{Min}$	$I_{OL} = 4\text{mA}$	54,74	0.25	0.4
			$I_{OL} = 8\text{mA}$	74	0.35	0.5
						V
$I_i$	Input current at maximum input voltage	$V_{CC} = \text{Max}$ $V_i = 7\text{V}$	J, K		0.1	mA
			Clock		0.1	
			Preset		0.2	
			Clear		0.2	
$I_{IH}$	High-level input current	$V_{CC} = \text{Max}$ $V_i = 2.7\text{V}$	J, K		20	μA
			Clock		20	
			Preset		40	
			Clear		40	
$I_{IL}$	Low-level input current	$V_{CC} = \text{Max}$ $V_i = 0.4\text{V}$	J, K		-0.4	mA
			Clock		-0.4	
			Preset		-0.8	
			Clear		-0.8	
$I_{OS}$	Short-circuit output current	$V_{CC} = \text{Max}$ (Note 2)	-20		-100	mA
$I_{CC}$	Supply current	$V_{CC} = \text{Max}$ (Note 3)	4		8	mA

Note 1: All typical values are at  $V_{CC} = 5\text{V}$ ,  $T_A = 25^\circ\text{C}$ .

Note 2: Not more than one output should be shorted at a time, and the duration should not exceed one second. For devices with feedback from the outputs, where shorting the outputs to ground may cause the outputs to change logic state an equivalent test may be performed where  $V_O = 2.25\text{V}$  and  $2.125\text{V}$  for 54 and 74 series, respectively with the minimum and maximum limits reduced by one half from their stated values.

This is very useful when using automatic test equipment.

Note 3: With all outputs open,  $I_{CC}$  is measured with the Q and  $\bar{Q}$  outputs high in turn. At the time of measurement the clock is grounded.

**Switching Characteristics,  $V_{CC} = 5V$ ,  $T_A = 25^\circ C$** 

PARAMETER*	FROM (INPUT)	TO (OUTPUT)	TEST CONDITION	MIN	TYP	MAX	UNIT
$f_{max}$			$C_L = 15\text{pF}, R_L = 2\text{k}\Omega$	25	33		MHz
$t_{PLH}$	Clock	Q or $\bar{Q}$		17	25		ns
$t_{PHL}$				22	30		ns
$t_{PLH}$	Clear	$\bar{Q}$		17	25		ns
$t_{PHL}$		Q		22	30		
$t_{PLH}$	Preset	Q		16	25		ns
$t_{PHL}$		$\bar{Q}$		22	30		

\*  $f_{max}$  = maximum clock frequency $t_{PLH}$  = propagation delay time low-to-level output. $t_{PHL}$  = propagation delay time high-to-low-level output